Standard Oxide Recipe - Unaxis PECVD

March 11, 2013

Equipment

Equipment Unaxis PECVD Manufacture Plasma-Therm Unaxis 78324

Platen size 10 in

Recipe

Recipe Name STD-OX

Gas 5% SiH₄/He 400 sccm

N₂O 900 sccm

Platen Power 25 W

RF Frequency 13.56 Mhz
Chamber Pressure 900 mTorr
Platen Temperature 250 C

Results ^a

Deposition Rate 516.98 A/min b

Uniformity 7.0% ^c
Refractive Index 1.498 ^d

Stress Level -83.49 MPascal ^e Etch Rate (100:1 BOE) 202.0 A/min ^f

- a: All data is updated as the date indicated above
- b: An average value from 20 min deposition
- c: Film thickness variation across a 4" wafer, defined as (max-min)/average
- d: An average value across a 4" wafer
- e: Measured with optical stress measurement tool
- f: An average value from 20 min etch